

Search Notes



Application/Control No.

10/811,807

Examiner

Tod T. Van Roy

**Applicant(s)/Patent under
Reexamination**

YUN, SANG BOK

Art Unit

2828

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Please see search history attached		
Spoke with examiner James Merete regarding gaps near facets	3/2/05	
Spoke with examiner James Merete regarding wet/dry etching	3/3/05	